

Search Notes

Application/Control No.

10/541,759

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

MIYAO ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
385	75	9/06	hnh
439	577		
439	676		
439	567		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR